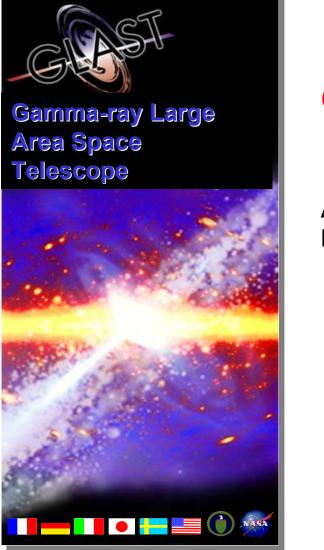


Beam test analysis meeting, January, 17, 2007





Charge injection DAC nonlinearity.

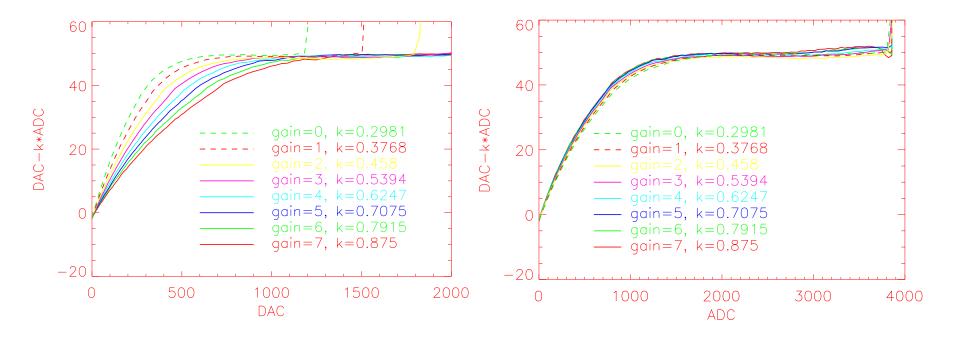
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LEX1 nonlinearity for different gain settings

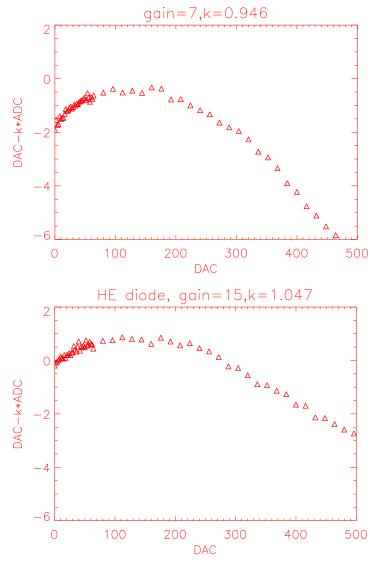


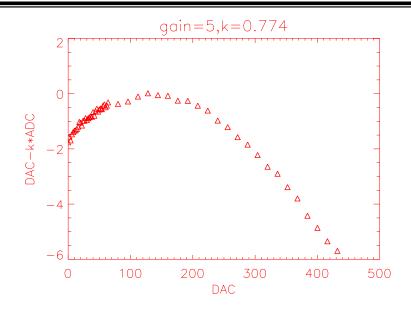
- Nonlinearity curve as a function of DAC changes with gain setting
- Nonlinearity curve as a function of ADC almost independent of gain setting
 - Consistent with a model containing some small parasitic feedback capacitance changing with output signal

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Zoom of small DAC region





- The part of nonlinearity curve at low DAC values contains significant changes of DAC/ADC slope happening at the same DAC value independently of gain (top left and top righ plots)
- Similar pattern could be seen for high energy diode (bottom left plot)
- This could be interpreted as DAC nonlinearity
- Difference in slope between region 0<DAC<32 and 300<DAC<400 is ~5%

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Discussion

- The same DAC is used for all channels of the same layer/side
 - DAC nonlinearity should be the same in both HE and LE diodes
 - From comparison of LE and HE plots on the previous slide possibly not all effect is due to DAC nonlinearity
- If we suppose that the DAC nonlinearity is present in the region DAC < 300, we shouldn't use the charge injection measurement in this region
- Proposal: let's try to do linear extrapolation to this region from 300<DAC<400 and see if it will help to get HEX8/LEX1=1